

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/704,755	FURUKAWA, HIDEAKI	
Examiner	Art Unit	
Daniel Pan	2183	

	SEAR	CHED	
Class	Subclass	Date	Examiner
712	29 225	11/17/2007	DP

INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
west pgp uspat jpoabs epoabs derwent IEEE IBM TD NPL 399/18-22 358/401 709/211,232 712/227, 248	11/17/2007	dp			
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